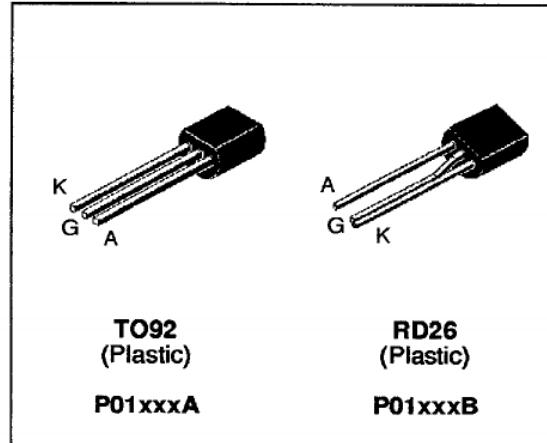


SENSITIVE GATE SCR

FEATURES

- $I_T(\text{RMS}) = 0.8\text{A}$
- $V_{DRM} = 100\text{V to } 400\text{V}$
- Low $I_{GT} < 1\mu\text{A}$ max to $< 200\mu\text{A}$



DESCRIPTION

The P01xxxA/B series of SCRs uses a high performance planar PNPN technology. These parts are intended for general purpose applications where low gate sensitivity is required.

ABSOLUTE RATINGS (limiting values)

Symbol	Parameter	Value	Unit
$I_T(\text{RMS})$	RMS on-state current (180° conduction angle)	0.8	A
$I_T(\text{AV})$	Mean on-state current (180° conduction angle)	0.5	A
I_{TSM}	Non repetitive surge peak on-state current (T_j initial = 25°C)	$t_p = 8.3 \text{ ms}$	8
		$t_p = 10 \text{ ms}$	7
I^2t	I^2t Value for fusing	0.24	A^2s
dI/dt	Critical rate of rise of on-state current $I_G = 10 \text{ mA}$ $dI/dt = 0.1 \text{ A}/\mu\text{s}$.	30	$\text{A}/\mu\text{s}$
T_{stg} T_j	Storage and operating junction temperature range	- 40, + 150 - 40, + 125	°C
T_l	Maximum lead temperature for soldering during 10s at 2mm from case	260	°C

Symbol	Parameter	Voltage				Unit
		A	B	C	D	
V_{DRM} V_{RRM}	Repetitive peak off-state voltage $T_j = 125^\circ\text{C}$ $R_{GK} = 1\text{K}\Omega$	100	200	300	400	V

P01xxxA/B

THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
R _{th(j-a)}	Junction to ambient	150	°C/W
R _{th(j-l)}	Junction to leads for DC	80	°C/W

GATE CHARACTERISTICS (maximum values)

P_{G (AV)} = 0.1 W P_{GM} = 2 W (tp = 20 µs) I_{GM} = 1 A (tp = 20 µs)

ELECTRICAL CHARACTERISTICS

Symbol	Test Conditions	Sensitivity					Unit		
		02	09	11	15	18			
I _{GT}	V _D =12V (DC) R _L =140Ω	T _j =25°C	MIN			4	15	0.5	
			MAX	200	1	25	50	5	
V _{GT}	V _D =12V (DC) R _L =140Ω	T _j =25°C	MAX	0.8			V		
V _{GD}	V _D =V _{DRM} R _L =3.3kΩ R _{GK} = 1 kΩ	T _j = 125°C	MIN	0.1			V		
V _{RGM}	I _{RG} =10µA	T _j = 25°C	MIN	8			V		
t _{gd}	V _D =V _{DRM} I _{TM} = 3 x I _{T(AV)} dI _G /dt = 0.1A/µs I _G = 10mA	T _j = 25°C	TYP	0.5			µs		
I _H	I _T = 50mA R _{GK} = 1 kΩ	T _j = 25°C	MAX	5			mA		
I _L	I _G =1mA R _{GK} = 1 kΩ	T _j = 25°C	MAX	6			mA		
V _{TM}	I _{TM} = 1.6A tp= 380µs	T _j = 25°C	MAX	1.93			V		
I _{DRM} I _{IRRM}	V _D = V _{DRM} R _{GK} = 1 kΩ V _R = V _{RRM}	T _j = 25°C	MAX	1			µA		
		T _j = 125°C	MAX	100			µA		
dV/dt	V _D =67%V _{DRM} R _{GK} = 1 kΩ	T _j = 125°C	MIN	25	25	50	100	30	V/µs
t _q	I _{TM} = 3 x I _{T(AV)} V _R =35V dI/dt=10A/µs tp=100µs dV/dt=10V/µs V _D = 67%V _{DRM} R _{GK} = 1 kΩ	T _j = 125°C	MAX	200			µs		

ORDERING INFORMATION

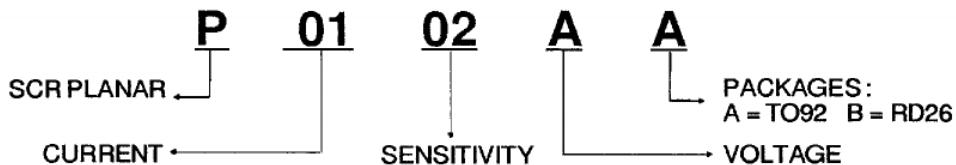


Fig.1 : Maximum average power dissipation versus average on-state current.

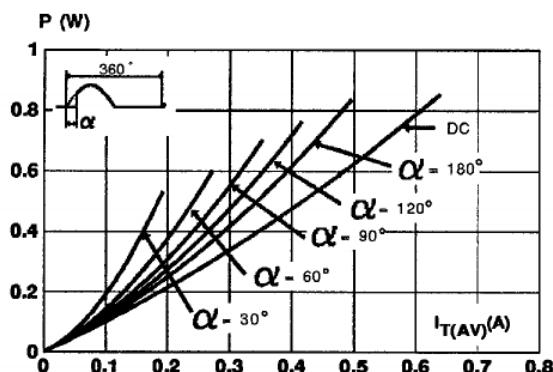


Fig.3 : Average on-state current versus lead temperature.

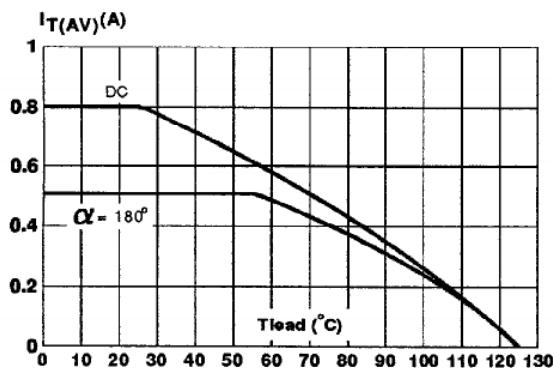


Fig.5 : Relative variation of gate trigger current and holding current versus junction temperature.

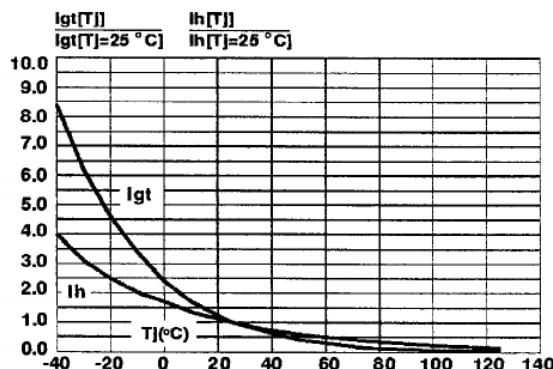


Fig.2 : Correlation between maximum average power dissipation and maximum allowable temperature (Tamb and Tlead).

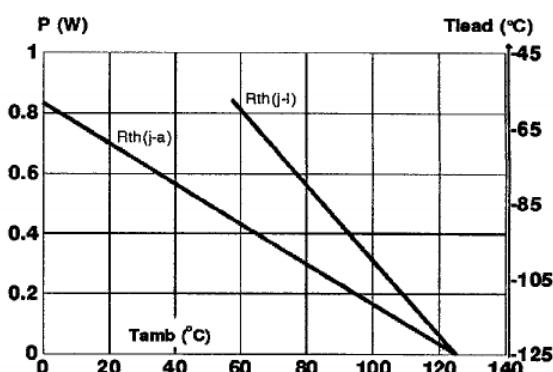


Fig.4 : Relative variation of thermal impedance junction to ambient versus pulse duration.

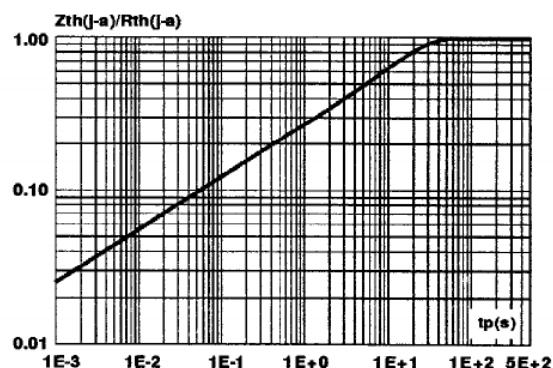
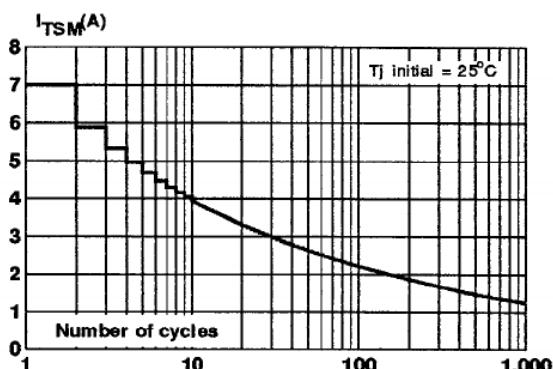


Fig.6 : Non repetitive surge peak on-state current versus number of cycles.



P01xxxA/B

Fig.7 : Non repetitive surge peak on-state current for a sinusoidal pulse with width : $t_p \leq 10\text{ms}$, and corresponding value of I^2t .

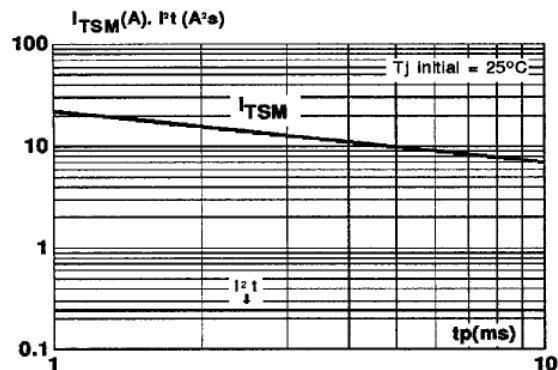


Fig.8 : On-state characteristics (maximum values).

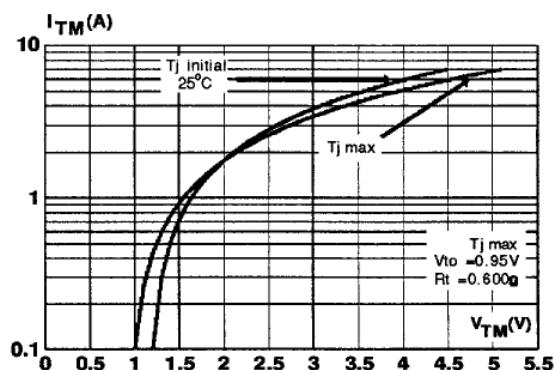
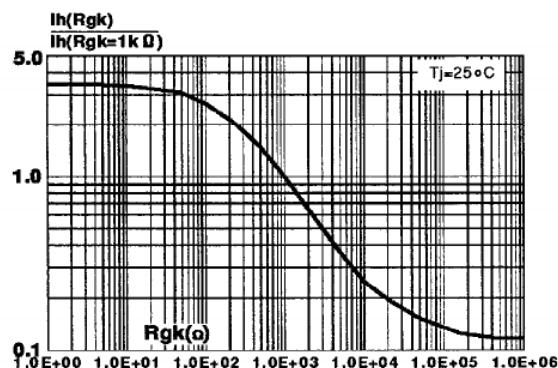
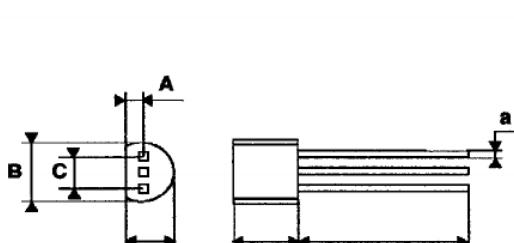


Fig.9 : Relative variation of holding current versus gate-cathode resistance (typical values).

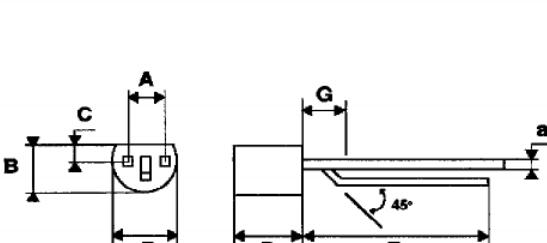


PACKAGE MECHANICAL DATA
TO92 (Plastic)


REF.	DIMENSIONS					
	Millimeters			Inches		
	Typ.	Min.	Max.	Typ.	Min.	Max.
A	1.35			0.053		
B			4.7			0.185
C	2.54			0.100		
D		4.4	4.8		0.173	0.189
E		12.7			0.500	
F			3.7			0.146
a			0.45			0.017

Marking : type number

Weight : 0.2 g

PACKAGE MECHANICAL DATA
RD26 (Plastic)


REF.	DIMENSIONS					
	Millimeters			Inches		
	Typ.	Min.	Max.	Typ.	Min.	Max.
A	2.54			0.100		
B			3.7			0.146
C	1.35			0.053		
D		4.4	4.8		0.173	0.189
E		12.7			0.500	
F			4.7			0.185
G			3.0			0.118
a			0.45			0.177

Marking : type number

Weight : 0.2 g

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